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eV-TEM: transmission electron microscopy with few-eV electrons
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Citation

Geelen, D. (2018, May 31). *eV-TEM: transmission electron microscopy with few-eV electrons*. *Casimir PhD Series*. Retrieved from <https://hdl.handle.net/1887/63484>

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Author: Geelen, D.

Title: eV-TEM: transmission electron microscopy with few-eV electrons

Issue Date: 2018-05-31



Casimir PhD Series, Leiden-Delft, 2018-13

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eV-TEM: TRANSMISSION ELECTRON MICROSCOPY WITH FEW-eV ELECTRONS

eV-TEM

TRANSMISSION ELECTRON MICROSCOPY
WITH FEW-eV ELECTRONS



Daniël Geelen